**EECS-130** 

# **Integrated Circuit Devices**

Midterm Exam # 1

FEBRUARY 13, 1996



### One 8½ x 11 sheet allowed for formula reference

## **Table 1-1 Physical constants**

Constant	Symbol	Magnitude
Avogadros number	$N_A$	6.023 x 10 <sup>23</sup> molecules/mol
Boltzmanns constant	k	$1.38 \times 10^{-23} \text{ J/K} = 8.62 \times 10^{-5} \text{ eV/K}$
Electronic charge	q	1.6 x 10 <sup>-19</sup> J
Electronvolt	eV	1.6 x 10-19 J
Free-electron mass	m	9.1 x 10 <sup>-31</sup> kg
Permittivity of free space	0	8.854 x 10 <sup>-14</sup> F/cm
Permeability of free space	$=\mu_0$	1.257 x 10 <sup>-8</sup> H/cm
Plancks constant	h	6.625 x 10-34 Js
Thermal voltage at 300K	VT	25.8 mV
Velocity of light	c	3 x 10 <sup>10</sup> cm/s

Midterm Exam # 10:p

1. A silicon abrupt junction, approximated by a step junction, has a doping of Boron 5 x 10 <sup>15</sup> cm <sup>-3</sup> and
Phosphorous = 1015 cm <sup>-3</sup> and a cross sectional area of 10 <sup>-4</sup> cm <sup>2</sup> . Assume the depletion approximation, no
applied voltage and $n_i = 10^{10}$ cm <sup>-3</sup> to: (40 points)

(a) calculate the built in voltage,  $\phi$  (5 pts)

(b) calculate $x_n$ , $x_p$ and the total depletion width. (5 pts)
(c) find the total positive ionic charge in the depletion width. (5 pts)
(d) calculate the electric field at the metallurgical junction ( $x = 0$ ). (5 pts)

(e)	sketch to a	relative	x-axis sc	cale the	charge	density	and	electric	field.	(5	pts)
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(f) calculate the values of the minority carriers in the bulk regions  $(n_p \text{ and } p_n)$ . (5 pts)

(g) draw the electron energy band diagram for the device. (5 pts)
(h) find the percentage of total depletion width in the p-depletion region, the n-depletion region. (5 pts)

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2. The  $1/C^2$  versus applied voltage relation in a silicon  $p^+ - n^- n^+$  junction diode is measured to have a form shown in Figure 1. The junction area is  $10^{-3}$  cm<sup>2</sup>. (25 points)

(a) Find the built-in voltage, \$\phi\$ (5 pts)

(b) Calculate the  $N_a$  and  $N_d$  concentrations in the  $p^+$  and n regions. (10 pts)

(c) Calculate the width of the *n*-region. (5 pts)

3. A silicon sample has a uniform dopant density of $N_d = 10^{16}$ cm <sup>-3</sup> and $N_a = 10^{14}$ cm <sup>-3</sup> . Assume that all the dopant atoms are fully ionized. The donor energy level is 0.049 eV below the conduction band and the acceptor energy level is 0.045 eV above the valence band. (35 points)
(a) Find the conductivity of the sample at room temperature. (7 pts)
(b) Find the Fermi energy level relative to the valence band edge $E_v$ or the conduction band edge, $E_c$ at 300° K. (7 pts)
(c) Find the equilibrium minority carrier concentration. (7 pts)

(d) Using the donor and acceptor energy levels given, find the fraction of the dopant atoms that are not ionized. (7 pts)
(a) Assuming the complete 2 cm long and has a cross sectional area of 2 mm <sup>2</sup> , calculate the complete
(e) Assuming the sample is 2 cm long and has a cross sectional area of 2 mm <sup>2</sup> , calculate the samples resistance. (7 pts)